

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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R. Talbot

In re the Application of

Makoto YONEZAWA

Application No.: New U.S. Patent Application

Filed: October 11, 2001

Docket No.: 110831

For: IMAGE PICKUP APPARATUS AND DEFECT INSPECTION SYSTEM FOR
PHOTOMASK

PRELIMINARY AMENDMENT

Director of the U.S. Patent and Trademark Office
Washington, D. C. 20231

Sir:

Prior to initial examination, please amend the above-identified application as follows:

IN THE CLAIMS:

Please replace claim 10 as follows:

A1
10. (Amended) An image pickup apparatus as set forth in claim 6, wherein each light receiving element of said image sensors has a charge storing ability able to store a charge generated in accordance with light striking it.

Please add new claims 14-16 as follows:

A2
-- 14. An image pickup apparatus as set forth in claim 7, wherein each light receiving element of said image sensors has a charge storing ability able to store a charge generated in accordance with light striking it. --

-- 15. An image pickup apparatus as set forth in claim 8, wherein each light receiving element of said image sensors has a charge storing ability able to store a charge generated in accordance with light striking it. --